

U.S. PATENT DOCUMENTS+							
		Document Number					
Examiner Initials*	Cite No.	Number Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
11/2	1	US-2004/0199815 A1	10-07-2004	Dinker et al.			
	2	US-2004/0153719 A1	08-05-2004	Achiwa et al.			
	3	US-2003/0233502 A1	12-18-2003	Murotani et al.			
V	4	US-2003/0046602 A1	03-06-2003	Hino et al.			

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Examiner Initials*	Cite No.'	For	eign Patent Do	cument	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Coturns, Lines, Where Relevant Passages or Relevant Figures Appear			
		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)	MM-DD-YYYY			T⁴		
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Examiner Signature	Scott Baderman	Date Considered	5/19/05	

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Substitute for form 1449A/PTO	Complete if Known			
	Application Number			
INFORMATION DISCLOSURE	Filing Date			
STATEMENT BY APPLICANT	First Named Inventor	NAKAGAWA, Yoshihito		
	Art Unit			
(use as many sheets as necessary)	Examiner Name			
Sheet 1 of	Attorney Docket Number	16869P-102400US		

U.S. PATENT DOCUMENTS+								
		Document Number						
Examiner Initials*	Cite No.1	Number Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			
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	FOREIGN PATENT DOCUMENTS										
Examiner	Cite No.1	Foreign Patent Document			Name of Patentee or	Pages, Columns, Lines, Where Relevant					
Initials*		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>6</sup> (# known)	Publication Date MM-DD-YYYY	Applicant of Cited Document	Passages or Relevant Figures Appear	Te			
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